TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC7MZ541FK

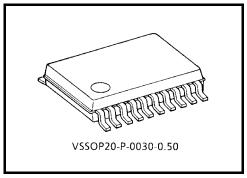
Low Voltage Octal Bus Buffer with 5 V Tolerant Inputs and Outputs

The TC7MZ541FK is a high performance CMOS octal bus buffer. Designed for use in 3.3 V systems, it achieves high speed operation while maintaining the CMOS low power dissipation.

The device is designed for low-voltage (3.3 V) VCC applications, but it could be used to interface to 5 V supply environment for both inputs and outputs.

The TC7MZ541FK is a non-inverting 3-state buffer having two active-low output enables. When either $\overline{OE}1$ or $\overline{OE}2$ are high, the terminal outputs are in the high-impedance state. This device is designed to be used with 3-state memory address drivers, etc.

All inputs are equipped with protection circuits against static discharge.

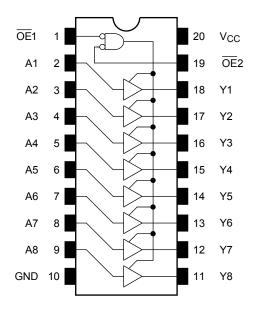


Weight: 0.03 g (typ.)

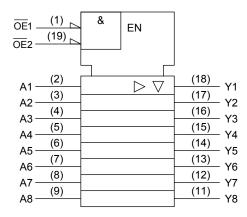
Features

- Low voltage operation: $V_{CC} = 2.0 \sim 3.6 \text{ V}$
- High speed operation: $t_{pd} = 6.5 \text{ ns (max)} (V_{CC} = 3.0 \sim 3.6 \text{ V})$
- Output current: $|I_{OH}|/I_{OL} = 24 \text{ mA (min) (V}_{CC} = 3.0 \text{ V)}$
- Latch-up performance: -500 mA
- Package: VSSOP (US20)
- Power down protection is provided on all inputs and outputs.
- Pin and function compatible with the 74 series (74AC/VHC/HC/F/ALS/LS etc.) 541 type.

Pin Assignment (top view)



IEC Logic Symbol



Truth Table

	Inputs	Outputs		
OE1	OE2	An	Outputs	
Н	Х	Х	Z	
Х	Н	Х	Z	
L	L	Н	Н	
L	L	L	L	

X: Don't care

Z: High impedance

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~7.0	V
DC input voltage	V _{IN}	-0.5~7.0	V
DC output voltage	\/a=	–0.5~7.0 (Note 2)	V
DC output voltage	Vout	-0.5~V _{CC} + 0.5 (Note 3)	V
Input diode current	lık	-50	mA
Output diode current	I _{OK}	±50 (Note 4)	mA
DC output current	lout	±50	mA
Power dissipation	P _D	180	mW
DC V _{CC} /ground current	I _{CC} /I _{GND}	±100	mA
Storage temperature	T _{stg}	<i>–</i> 65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: Output in off-state

Note 3: High or low state. I_{OUT} absolute maximum rating must be observed.

Note 4: $V_{OUT} < GND, V_{OUT} > V_{CC}$

Operating Ranges (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage	V _{CC}	2.0~3.6	
Supply voltage	vCC	1.5~3.6 (Note 2)	V
Input voltage	V _{IN}	0~5.5	V
Output voltage	V _{OUT}	0~5.5 (Note 3)	V
		0~V _{CC} (Note 4)	V
Output current	I _{OH} /I _{OL}	±24 (Note 5)	mA
Output current	iOH/iOL	±12 (Note 6)	ША
Operating temperature	T _{opr}	-40~85	°C
Input rise and fall time	dt/dv	0~10 (Note 7)	ns/V

Note 1: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

Note 2: Data retention only

Note 3: Output in off-state

Note 4: High or low state

Note 5: $V_{CC} = 3.0 \sim 3.6 \text{ V}$

Note 6: $V_{CC} = 2.7 \sim 3.0 \text{ V}$

Note 7: $V_{IN} = 0.8 \sim 2.0 \text{ V}, V_{CC} = 3.0 \text{ V}$

Electrical Characteristics

DC Characteristics ($Ta = -40 \sim 85$ °C)

Characte	Characteristics Symbol Test Condition					Min	Max	Unit	
Cildiacte	ELISTICS	Symbol	Test Condition		V _{CC} (V)	IVIIII	IVIAX	Unit	
Input voltage	High level	V_{IH}		_	2.7~3.6	2.0	_	V	
input voitage	Low level	V_{IL}		_	2.7~3.6	_	0.8	V	
				I _{OH} = -100 μA	2.7~3.6	V _{CC} - 0.2	_		
	High level	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -12 mA	2.7	2.2	_		
				I _{OH} = -18 mA	3.0	2.4	_		
Output voltage	Output voltage			I _{OH} = -24 mA	3.0	2.2	_	V	
				I _{OL} = 100 μA	2.7~3.6	_	0.2		
Low level	\/ - ·	\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	I _{OL} = 12 mA	2.7	_	0.4			
	Low level	V _{OL}	VOL	$V_{IN} = V_{IH}$ or V_{IL}	I _{OL} = 16 mA	3.0	_	0.4	
			I _{OL} = 24 mA	3.0	_	0.55	,		
Input leakage cu	rrent	I _{IN}	V _{IN} = 0~5.5 V		2.7~3.6	_	±5.0	μА	
3 state output of	0 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 -		$V_{IN} = V_{IH}$ or V_{IL}		2.7~3.6	_	±5.0	μА	
3-state output off-state current I _{OZ}		102	V _{OUT} = 0~5.5 V		2.1~3.0				
Power off leakag	ge current	loff	$V_{IN}/V_{OUT} = 5.5 \text{ V}$				10.0	μΑ	
Quiescent supply current		loo	V _{IN} = V _{CC} or GND		2.7~3.6	_	10.0		
Quiescent suppi	y current	icc	V _{IN} /V _{OUT} = 3.6~5.5 V		2.7~3.6	_	±10.0	μА	
Increase in I _{CC} p	per input	Δl _{CC}	$V_{IH} = V_{CC} - 0.6 V$ 2.7				500		

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AC Characteristics ($Ta = -40 \sim 85$ °C)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Min	Max	Unit
Drangation delay time	t _{pLH}	Figure 1 Figure 2	2.7	_	7.5	20
Propagation delay time	t _{pHL}	Figure 1, Figure 2	3.3 ± 0.3	1.5	6.5	ns
Output enable time	t _{pZL}	Figure 1, Figure 3	2.7	_	9.5	- ns
	t _{pZH}		3.3 ± 0.3	1.5	8.5	
Output disable time	t _{pLZ}	Figure 1, Figure 3	2.7		8.5	ns
Output disable time	t _{pHZ}	rigure 1, rigure 3	3.3 ± 0.3	1.5	7.5	110
Output to output skew	t _{osLH}	(NI ₂ A ₂)	2.7			ns
Output to output skew	t _{osHL}	(Note)	3.3 ± 0.3		1.0	10

Note: This parameter is guaranteed by design.

 $(t_{OSLH} = |t_{PLHm} - t_{PLHn}|, t_{OSHL} = |t_{PHLm} - t_{PHLn}|)$

Dynamic Switching Characteristics

(Ta = 25°C, Input: $t_r = t_f = 2.5$ ns, $C_L = 50$ pF, $R_L = 500$ Ω)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Quiet output maximum dynamic V_{OL}	V _{OLP}	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	8.0	V
Quiet output minimum dynamic V _{OL}	V _{OLV}	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	0.8	V

Capacitive Characteristics (Ta = 25°C)

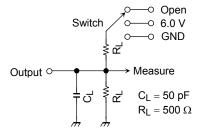
Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Input capacitance	C _{IN}	_	3.3	7	pF
Output capacitance	C _{OUT}	_	3.3	8	pF
Power dissipation capacitance	C _{PD}	$f_{IN} = 10 \text{ MHz}$ (No	te) 3.3	40	pF

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 \text{ (per bit)}$

AC Test Circuit



Parameter	Switch
t _{pLH} , t _{pHL}	Open
t _{pLZ} , t _{pZL}	6.0 V
t _{pHZ} , t _{pZH}	GND

Figure 1

AC Waveform

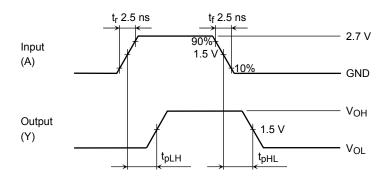


Figure 2 t_{pLH}, t_{pHL}

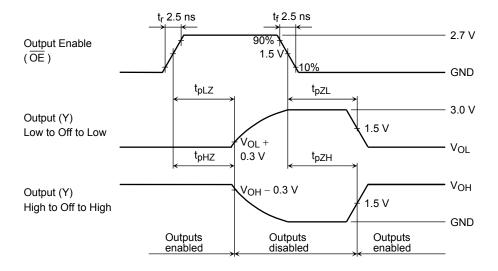
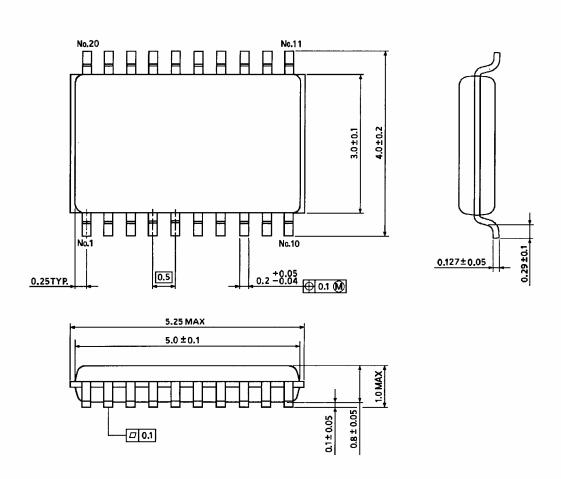


Figure 3 t_{pLZ} , t_{pHZ} , t_{pZL} , t_{pZH}

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Package Dimensions



Weight: 0.03 g (typ.)

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20070701-EN GENERAL

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